

FORM PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 12054-0059	SERIAL NO. 10/576,321
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Kazunari KURITA et al.	
				FILING DATE 04/19/2006	GROUP ART UNIT Not yet assigned

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
/MC/	1.	6,544,656	04/08/2003	ABE et al.			
/MC/	2.	2002/0179003	12/05/2002	IIDA et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES NO PART.
/MC/	3.	WO00/55397	09/21/2000	PCT			<input checked="" type="checkbox"/> X
/MC/	4.	2000-100631	04/07/2000	JAPAN			<input checked="" type="checkbox"/> X
/MC/	5.	1087041A1	03/28/2001	EUROPE		<input checked="" type="checkbox"/> X	
/MC/	6.	2000-344598	12/12/2000	JAPAN			<input checked="" type="checkbox"/> X
/MC/	7.	WO01/79593	10/25/2001	PCT			<input checked="" type="checkbox"/> X
/MC/	8.	1229155	08/07/2002	EUROPE		<input checked="" type="checkbox"/> X	
/MC/	9.	2003-286094	10/07/2003	JAPAN			<input checked="" type="checkbox"/> X
/MC/	10.	WO03/092065	11/06/2003	PCT			<input checked="" type="checkbox"/> X
/MC/	11.	WO2004/008521	01/22/2004	PCT			<input checked="" type="checkbox"/> X

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

/MC/	12.	M. Akatsuka et al., "Pinning Effect on Punched-Out Dislocations in Silicon Wafers Investigated Using Indentation Method", Jpn. J. Appl. Phys., Vol. 36 (1997), pgs. 1422-1425
/MC/	13.	K. Sueoka et al., "Effect of Oxide Precipitate Sizes on the Mechanical Strength of Czochralski Silicon Wafers", Jpn. J. Appl. Phys., Vol. 36 (1997), pgs. 7095-7099
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EXAMINER	/Marissa Chaet/	DATE CONSIDERED	07/20/2007
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.